

Instrument Billing Rates & Policies

Fee Schedule

MARTECH analytic facilities are provided on a fee basis of \$50/unit for internal users. The billing unit is **one hour** for the following instruments:

Billed \$50/hour	
SPM/AFM	SEM & EDS
X-ray Diffraction (powder, thin-film, Laue and hi/low-T)	
XPS/ESCA	
Magneto-transport measurements on SQUID or VSM platforms	

The billing unit is different for the following instruments:

Billed \$50/8-hour period	Billed \$50/4-hour period
SQUID Magnetometer	VSM (ambient, hi/low-T)

The following instruments are **not billed**:

Not billed	
ellipsometry	profilometry
sputter coating for the SEM	

Cost and no-Cost Services

Users **are billed** for the following services:

- Actual instrument time used for the acquisition of experimental data

Users **are not billed** for the following services:

- Instrument training
- Consultation & collaboration
- Use of computer software and databases for data analysis
- Time required to set-up or configure an instrument for use

Cost and no-Cost Consumables

Users **are not billed** for the following consumables:

- Computer printer consumables (*e.g.* ink cartridges, paper)
- General lab consumables (*e.g.* gloves, whipes, weigh papers)
- General lab solvents (*e.g.* MeOH, EtOH, acetone)
- Cryofluids (*e.g.* LHe, LN₂)
- Pressurized gasses (*e.g.* Ar, N₂)
- Sample mounting materials
 - SEM sample mounting materials (*e.g.* pucks, carbon tape)
 - XPS sample mounting materials (*e.g.* pucks, tabs)
 - SQUID sample mounting materials (*e.g.* straws, tapes, capsules)
 - XRD sample mounting materials (*e.g.* tapes, grease)
 - SPM/AFM sample mounting materials (*e.g.* tapes, glues, slides)
- Consumable standards (*e.g.* XRD internal standards)—**when used responsibly**

Users **are billed at cost** for the following consumables:

- AFM tips
- Laue camera film

Price schedules are available upon request.

Extraordinary Circumstances

Users are not billed for instrument time in the event of catastrophic instrument failure, power outage, or for cases in which the instrument performance is sub-standard. Users are also not billed for the normal failure of instrument components **under normal responsible operation**: *e.g.* electronics failure, failure of X-ray tube, broken SEM filament, *etc.*

Billing Process

The user is required to submitted a totaled instrument use form to Dr. Eric Lochner during the first week of each month. **A failure to honestly and accurately log and submit instrument time will result in a loss of instrument privileges.** Dr. Eric Lochner's contact information:

Dr. Eric Lochner
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